HQ:NSC35/Cr-Au BS

AFM Probe with 3 Different Gold Coated Soft Tapping Mode AFM Cantilevers

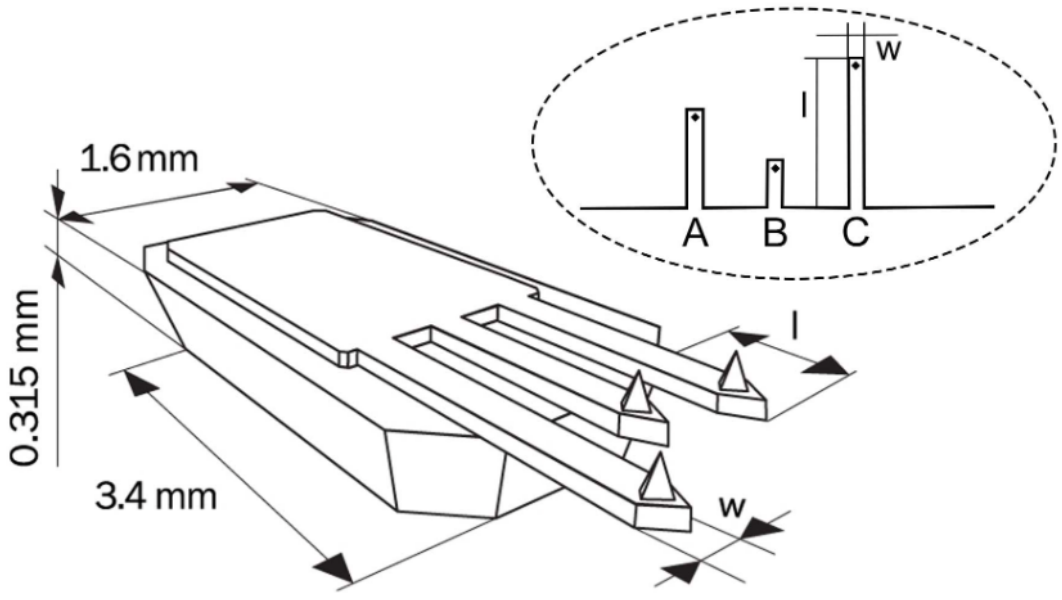
AFM probes of the HQ:NSC35 series have three different soft tapping mode AFM cantilevers on one side of the holder chip. They can be used in various applications.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

The gold reflective coating enhances the laser reflectivity of the AFM cantilevers in air and liquids.

Coating

Reflective Gold



AFM Probe Specifications

AFM Tip

SHAPE	HEIGHT	FULL CONE ANGLE	RADIUS
Rotated	15 µm (12 – 18 µm)*	40°	< 8 nm

AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	8.9 N/m (2.7 – 24 N/m)*	205 kHz (130 – 290 kHz)*	110 µm (1 – 115µm)*	35 µm (32 – 38µm)*	2µm (1.5 – 2.5 µm)*
Cantilever B	Beam	16 N/m (4.8 – 44 N/m)*	300 kHz (185 – 430 kHz)*	90 µm (1 – 95µm)*	35 µm (32 – 38µm)*	2µm (1.5 – 2.5 µm)*
Cantilever C	Beam	5.4 N/m (1.7 – 14 N/m)*	150 kHz (95 – 205 kHz)*	130 µm (1 – 135µm)*	35 µm (32 – 38µm)*	2µm (1.5 – 2.5 µm)*

* typical values